

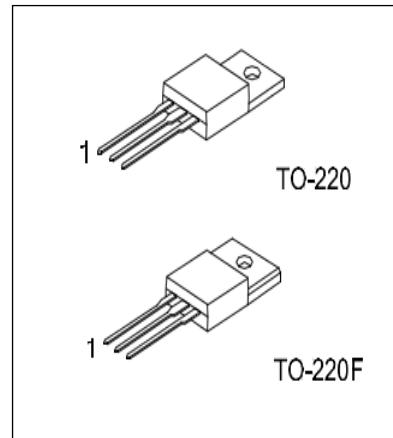
9 Amps, 500Volts N-Channel MOSFET

■ Description

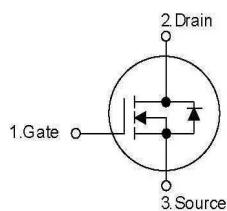
The ET840 N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as switching regulators, switching converters, solenoid, motor drivers, relay drivers.

■ Features

- $R_{DS(ON)} = 0.80\Omega @ V_{GS} = 10\text{ V}$
- Low gate charge (typical 30nC)
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability



■ Symbol



■ Absolute Maximum Ratings ($T_c=25^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Ratings		Units
		TO-220	TO-220F	
Drain-Source Voltage	V_{DSS}	500		V
Gate-Source Voltage	V_{GSS}	± 30		V
Drain Currentet Continuous	$T_c=25^\circ\text{C}$	I_D	9.0	A
	$T_c=100^\circ\text{C}$		5.4	A
Drain Current Pulsed (Note 1)	I_{DP}	36	36*	A
Avalanche Energy	Repetitive (Note 1)	E_{AR}	13.9	mJ
	Single Pulse (Note 2)	E_{AS}	360	mJ
Peak Diode Recovery dv/dt (Note 3)	dv/dt	4.5		V/ns
Total Power Dissipation	$T_c=25^\circ\text{C}$	P_D	139	W
	Derate above 25°C		1.11	W/°C
Junction Temperature	T_J	+150		°C
Storage Temperature	T_{STG}	-55~+150		°C

* Drain current limited by maximum junction temperature.

■ Thermal Characteristics

Parameter	Symbol	Ratings		Units
		TO-220	TO-220F	
Thermal Resistance Junction-Ambient	R_{thJA}	62.5		$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Case-to-Sink Typ.	R_{thCS}	0.5	--	
Thermal Resistance Junction-Case	R_{thJC}	0.90	2.75	

■ Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless Otherwise specified.)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	500	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=500\text{V}, V_{GS}=0\text{V}$	--	--	1	μA
		$V_{DS}=400\text{V}, T_c=125^{\circ}\text{C}$	--	--	10	μA
		$V_{GS}=30\text{V}, V_{DS}=0\text{V}$	--	--	100	nA
Gate-Body Leakage Current	I_{GSS}	$V_{GS}=-30\text{V}, V_{DS}=0\text{V}$	--	--	-100	nA
Breakdown Voltage Temperature Coefficient	$\Delta \text{BV}_{DSS}/\Delta T_J$	$I_D=250\mu\text{A}$	--	0.6	--	V/ $^{\circ}\text{C}$
On Characteristics						
Gate Threshold Voltage	$V_{GS(\text{TH})}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2.0	--	4.0	V
Static Drain-Source On-Resistance	$R_{DS(\text{ON})}$	$V_{DS}=10\text{V}, I_D=4.5\text{A}$	--	0.65	0.80	Ω
Dynamic Characteristics						
Input Capacitance	C_{ISS}	$V_{DS}=25\text{V}, V_{GS}=0\text{V}, f=1\text{MHz}$	--	870	--	pF
Output Capacitance	C_{OSS}		--	130	--	pF
Reverse Transfer Capacitance	C_{RSS}		--	25	--	pF
Switching Characteristics						
Turn-On Delay Time	$t_{D(\text{ON})}$	$V_{DD}=250\text{V}, I_D=9.0\text{A}, R_G=25\Omega$ (Note 4, 5)	--	20	--	ns
Rise Time	t_R		--	70	--	ns
Turn-Off Delay Time	$t_{D(\text{OFF})}$		--	90	--	ns
Fall Time	t_F		--	60	--	ns
Total Gate Charge	Q_G	$V_{DS}=400\text{V}, I_D=9.0\text{A}, V_{GS}=10\text{V}$ (Note 4, 5)	--	30	--	nC
Gate-Source Charge	Q_{GS}		--	4.0	--	nC
Gate-Drain Charge	Q_{GD}		--	15	--	nC
Drain-Source Diode Characteristics						
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS}=0\text{V}, I_{SD}=9.0\text{A}$	--	--	1.4	V
Continuous Drain-Source Current	I_{SD}		--	--	9.0	A
Pulsed Drain-Source Current	I_{SM}		--	--	36.0	A
Reverse Recovery Time	t_{RR}	$I_{SD}=9.0\text{A}, dI_{SD}/dt=100\text{A}/\mu\text{s}$ (Note 4)	--	340	--	ns
Reverse Recovery Charge	Q_{RR}		--	3.0	--	μC

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. $L = 8\text{mH}$, $I_{AS} = 9.0\text{ A}$, $V_{DD} = 50\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^{\circ}\text{C}$
3. $I_{SD} \leq 9.0\text{ A}$, $dI/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq \text{BV}_{DSS}$, Starting $T_J = 25^{\circ}\text{C}$
4. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
5. Essentially independent of operating temperature

■ Typical Characteristics

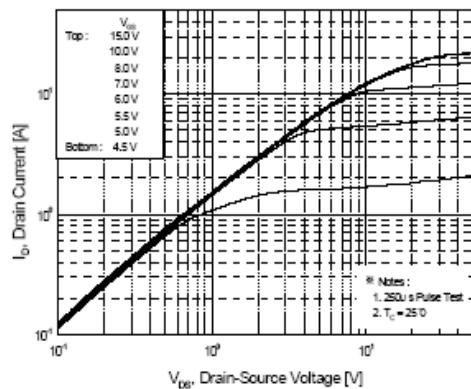


Figure 1. On-Region Characteristics

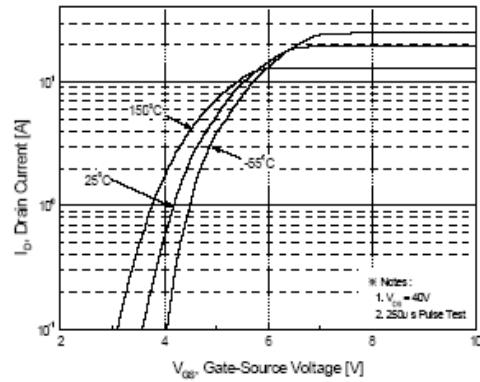


Figure 2. Transfer Characteristics

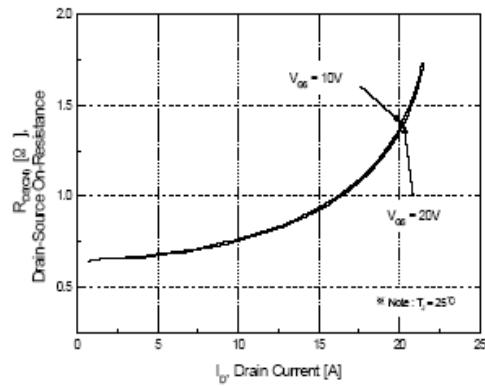


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

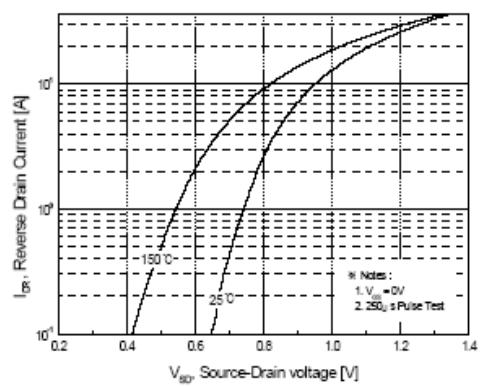


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

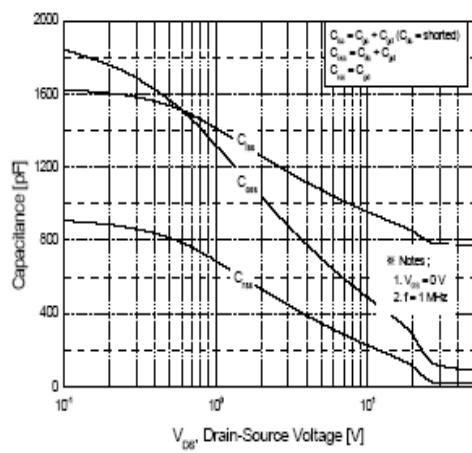


Figure 5. Capacitance Characteristics

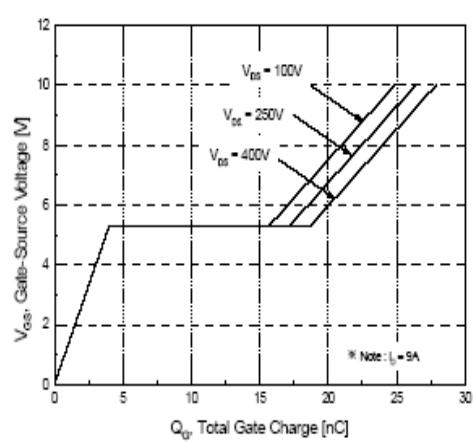
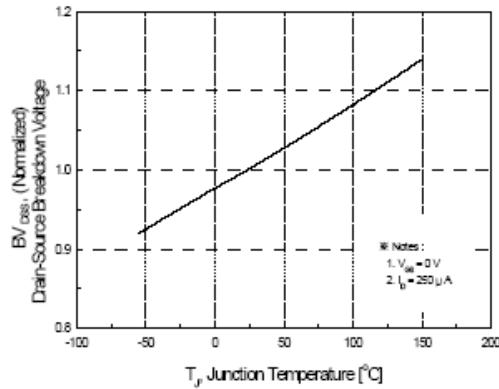
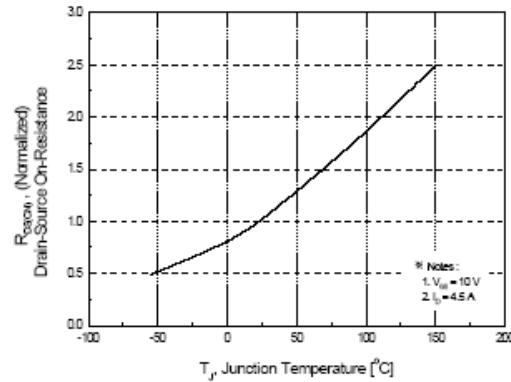


Figure 6. Gate Charge Characteristics

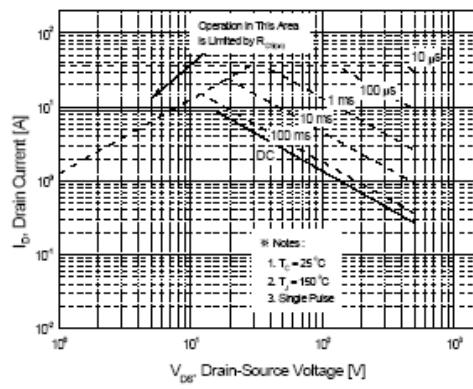
■ Typical Characteristics (Continued)



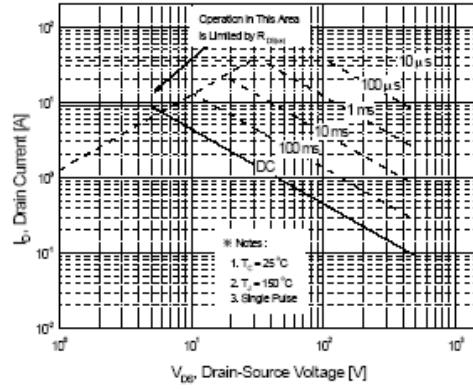
**Figure 7. Breakdown Voltage Variation
vs Temperature**



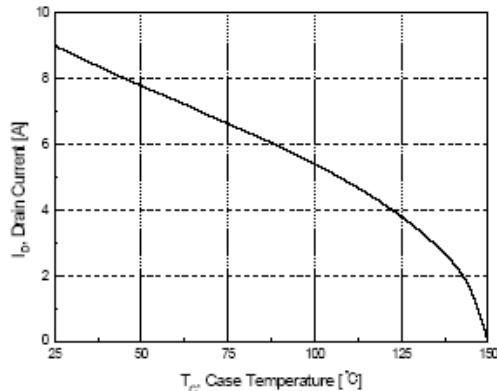
**Figure 8. On-Resistance Variation
vs Temperature**



**Figure 9-1. Maximum Safe Operating Area
for TO220**



**Figure 9-2. Maximum Safe Operating Area
for TO220F**



**Figure 10. Maximum Drain Current
vs Case Temperature**

■ Typical Characteristics (Continued)

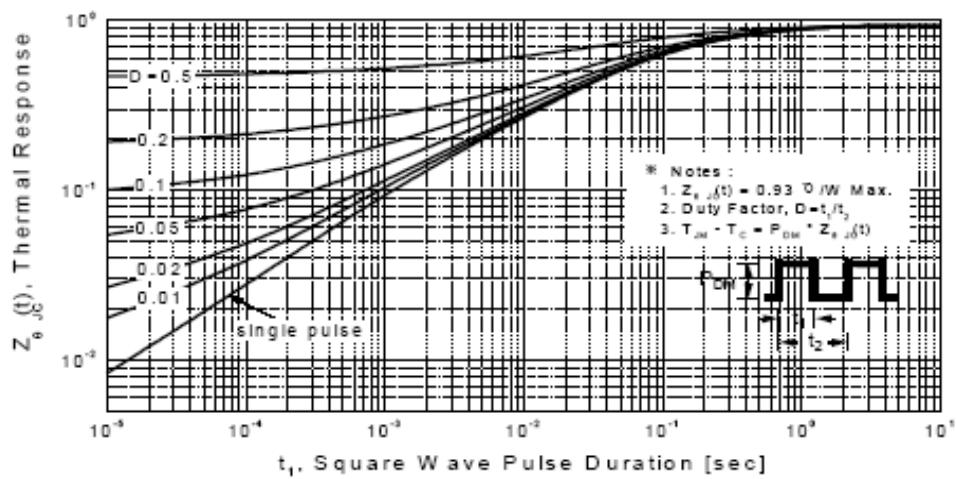


Figure 11-1. Transient Thermal Response Curve for TO220

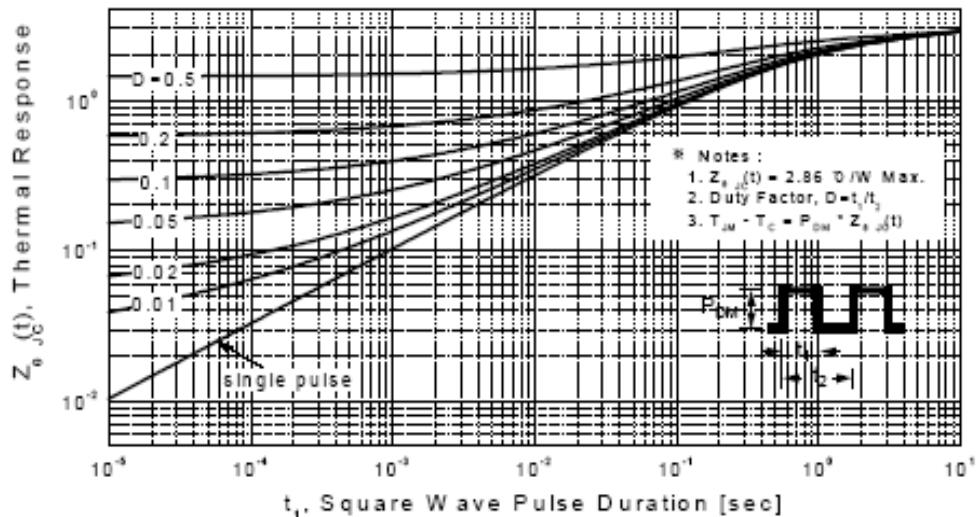


Figure 11-2. Transient Thermal Response Curve for TO220F